



IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 17.0005

CB Certificate No.: 50600201 ITL

Schedule Number: IECQ-L ULTW 17.0005-S Rev No.: 5 Revision Date: 2023/10/18 Page 1 of 1

Appendix-1 (50600201 ITL) Schedule of Scope to Certificate of Approval

Description test	Standard
Time Dependent Dielectric Breakdown (TDDB)	JESD92, JEP159, JEP001-1, JEP001-2, Lab SOP:RMSG-QWLR001-003
Hot Carrier Injection (HCI)	JESD28, JESD60, JEP001-2, Lab SOP:RMSG-QWLR001-001
Bias Temperature Instability (BTI)	JESD90, JEP001-2, Lab SOP:RMSG-QWLR001-002
Electromigration (EM)	JEP001-1, JESD33, JESD87 Lab SOP:RMSG-QWLR001-005
Stress Migration (SM)	JEP001-1, JEP139, JESD214 Lab SOP :RMSG-QWLR001-006
High Temperature Operating Life (HTOL)	AEC-Q100, JESD22-A108, JEP001-3, Lab SOP:RMSG-QRAI003-001
Low Temperature Operating Life (LTOL)	AEC-Q100, JESD22-A108, JEP001-3 Lab SOP:RMSG-QRAI004-001
Early Life Failure Rate (ELFR)	AEC-Q100, AEC Q100-008, JEP001-3 Lab SOP:RMSG-QRAI002-001
NVM Endurance, Data Retention, and Operational Life (EDR)	AEC-Q100, AEC Q100-005 Lab SOP:RMSG-QRAI005-001
Scanning Electrom Microscope (SEM)	Lab SOP: RMSG-RSE5500-001

Technical Reviewer of DQS: Michael Chou Date: 10/18/2023

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